



<u>IN THE UNITED STATES PATENT AND TRADEMARK OFFICE</u>

: Martin MILLER et al.

Serial No.

10/673,735

Filed

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September 29, 2003

Title

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METHOD OF ANALYZING SERIAL DATA STREAMS

Art Unit

:

2133

Examiner

To Be Assigned

745 Fifth Avenue New York, NY 10151

I hereby certify that this correspondence is being deposited with the United States Postal Service as first class mail in an envelope addressed to: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450, on December 3, 2004.

William S. Frommer, Reg. No. 25,506

Name of Applicant, Assignee or Registered Representative

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December 3, 2004

Date of Signature

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Sir

In compliance with the duty of disclosure set forth in 37 C.F.R. 1.56, Applicants are filing this Supplemental Information Disclosure Statement, the accompanying form PTO-1449 and the documents noted thereon.

So far as Applicants are aware, this Supplemental Information Disclosure Statement is being filed before the mailing date of the first Office Action on the merits.

The filing of this Information Disclosure Statement is not an admission that the documents identified herein constitute prior art to the present application.

It is believed that no fees are required by the instant submission as it is prior to receipt of the first Office Action in this application. However, if any fees are required, or if any overpayment has been made, please charge Deposit Acct. No. 50-0320.

Respectfully submitted,

FROMMER LAWRENCE & HAUG LLP Attorney for Applicants

William S. Frommer

Reg. No. 25,506 (212) 588-0800

Encs. - PTO Form 1449

										
Based on Form PTO-1449 (3/90)					ATTY. DOCKET NO. 455610-2590.2		SERIAL NO. 10/673,735			
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Based on Form PTO-1449 (3/90)				ATTY. DOCKET NO. SERIAL NO. 10/673,735						
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	во	Design of FIR Filters b	Design of FIR Filters by Windowing, MIT Website, (http://web.mit.edu/6.555/www/fir.html)							
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-	ВЈ	Advanced Analysis of	f High-Speed Digital Commun	nication Waveforms, Hewlett Packard	, June 27, 1994				
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	ВМ	Communications Sign	Communications Signal Analyzer, Tektronix Website (www.tektronix.com/optical)						
	BN	RT-Eye™ Serial Data	RT-Eye™ Serial Data Compliance and Analysis Software, Tektronix Website (www.Tektronix.com/accessories)						
	во	Design of FIR Filters	Design of FIR Filters by Windowing, MIT Website, (http://web.mit.edu/6.555/www/fir.html)						
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